Application No. 10/815,567 Attorney Docket No. MP1534

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AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions and listings of claims in the application:

(Currently amended) A method comprising:

monitoring one or more sensor outputs, each of the one or more sensor outputs measuring a power consumption property of a chip; and

recording a <u>total</u> time that at least one of the <u>each</u> of the <u>one</u> or <u>more</u> sensor outputs indicates an existence of the power consumption property at a <u>corresponding</u> predetermined value.

- 2. (Original) The method of claim 1, wherein the power consumption property of the chip comprises temperature, and the temperature comprises a temperature range including one or more temperatures.
- 3. (Currently amended) The method of claim 2, wherein each sensor output corresponds to a <u>corresponding</u> temperature range, and indicates the <u>an</u> existence of <u>a</u> temperature of the chip falling within the corresponding temperature range as the one or more temperatures measured at the corresponding sensor output.
- 4. (Currently amended) The method of claim 1, wherein the power consumption property of the chip comprises voltage drop, and the voltage drop range comprises a voltage drop range including includes one or more voltage drops.

- 5. (Currently amended) The method of claim 4, wherein each sensor output corresponds to a <u>corresponding</u> voltage drop range, and each sensor output indicates the <u>an</u> existence of a voltage drop <u>falling within the corresponding voltage drop range as</u> measured at the corresponding <u>sensor</u> output.
- 6. (Currently amended) A method for analyzing operation of a chip executing an application, the method comprising:

monitoring one or more parts of the application;

obtaining event data from a sensor attached to the chip, the event data including one or more times that one or more sensor outputs of the sensor indicates an existence of a power consumption property of the chip being at least a corresponding predetermined value as measured at the one or more sensor outputs; and

for at least one a first part of the one or more parts of the application <u>being</u> monitored, correlating the event data with <u>one or more instruction addresses associated</u> with the <u>first part parts</u> of the application.

- 7. (Original) The method of claim 6, wherein the power consumption property comprises temperature.
- 8. (Original) The method of claim 6, wherein the power consumption property comprises voltage drop.
- 9. (Currently amended) An apparatus for analyzing operation of a chip executing an application, the apparatus comprising:

circuitry capable of:

monitoring one or more parts of the application;

obtaining event data from a sensor attached to the chip, the event data including one or more times that one or more sensor outputs of the sensor indicates an existence of a power consumption property of the chip being at least a corresponding predetermined value as measured at the one or more sensor outputs; and

for at least one <u>a first part</u> of the <u>one or more</u> parts of the application <u>being</u> <u>monitored</u>, correlating the event data with <u>one or more instruction addresses associated</u> <u>with the first part parts</u> of the application.

- 10. (Original) The apparatus of claim 9, wherein the power consumption property of the chip comprises temperature, and the temperature comprises a temperature range including one or more temperatures.
- 11. (Currently amended) The apparatus of claim 10, wherein each sensor output corresponds to a <u>corresponding</u> temperature range, and indicates the <u>an</u> existence of <u>a temperature of the chip falling within the corresponding temperature range as the one or more temperatures</u> measured at the corresponding sensor output.
- 12. (Original) The apparatus of claim 9, wherein the power consumption property of the chip comprises voltage drop, and the voltage drop comprises a voltage drop range including one or more voltage drops.
- 13. (Currently amended) The apparatus of claim 12, wherein each sensor output corresponds to a <u>corresponding</u> voltage drop range, and each sensor output indicates the <u>an</u> existence of a voltage drop <u>falling</u> within the <u>corresponding</u> voltage drop <u>range</u> as measured at the corresponding <u>sensor</u> output.

14. (Currently amended) A system for analyzing operation of a chip executing an application, the system comprising:

circuitry on a first node, the circuitry connected to the chip and capable of:

monitoring one or more parts of the application;

obtaining event data from a sensor attached to the chip, the event data including one or more times that each of one or more sensor outputs of the sensor indicates an existence of a power consumption property of the chip being at least a corresponding predetermined value as measured at the one or more sensor outputs; and

for at least one <u>a first part</u> of the <u>one or more</u> parts of the application, correlating the event data with <u>one or more instruction addresses associated with</u> the <u>first part</u> parts of the application; and

a performance analyzer on a second node, the performance analyzer communicatively coupled to the circuitry on the first node, the performance analyzer to use the correlated information.

- 15. (Previously presented) The system of claim 14, wherein the power consumption property of the chip comprises temperature, and the temperature comprises a temperature range including one or more temperatures.
- 16. (Currently amended) The system of claim 15, wherein each sensor output corresponds to a temperature range, and indicates the <u>an</u> existence of <u>a temperature of the chip falling within the corresponding temperature range as the one or more temperatures measured at the corresponding sensor output.</u>

- 17. (Currently amended) The system of claim 14, wherein the power consumption property of the chip comprises voltage drop, and wherein the voltage drop comprises a voltage drop range includes including one or more voltage drops.
- 18. (Currently amended) The system of claim 17, wherein each sensor output corresponds to a voltage drop range, and each sensor output indicates the <u>an</u> existence of a voltage drop <u>falling</u> within the <u>corresponding voltage drop range as</u> measured at the corresponding sensor output.
- 19. (Currently amended) An article comprising a A machine readable medium memory having storing machine-accessible instructions, the instructions when executed by a machine, result in the following cause the machine to:

monitor monitoring one or more parts of the instructions;

obtain obtaining event data from a sensor attached to the machine, the event data including one or more times that each of one or more sensor outputs indicates an existence of a power consumption property of a chip being at least a predetermined value; and

correlate for at least one of the parts of the instructions, correlating the event data with the <u>one or more</u> parts of the instructions <u>being monitored</u>.

20. (Currently amended) The article memory of claim 19, wherein the power consumption property of the chip comprises a temperature range, and wherein the temperature range includes one or more temperatures.

- 21. (Currently amended) The article memory of claim 20, wherein each sensor output corresponds to a corresponding temperature range, and indicates the an existence of a temperature of the machine falling within the corresponding temperature range as the one or more temperatures measured at the corresponding sensor output.
- 22. (Currently amended) The article memory of claim 19, wherein the power consumption property of the chip comprises voltage drop range, and wherein the voltage drop comprises a voltage drop range including includes one or more voltage drops.
- 23. (Currently amended) The article memory of claim 22, wherein each sensor output corresponds to a voltage drop range, and each sensor output indicates the an existence of a voltage drop falling within the corresponding voltage drop range as measured at the corresponding sensor output.
- 24. (Currently amended) A method for analyzing operation of a chip based on an executing application, the method comprising:

monitoring one or more portions of the executing application;

<u>obtaining one or more instruction addresses corresponding to the one or more</u> portions;

correlating the monitored one or more portions of the executing application corresponding to the one or more instruction addresses obtained with power consumption data obtained by a sensor on the chip; and

storing data corresponding to the correlating.